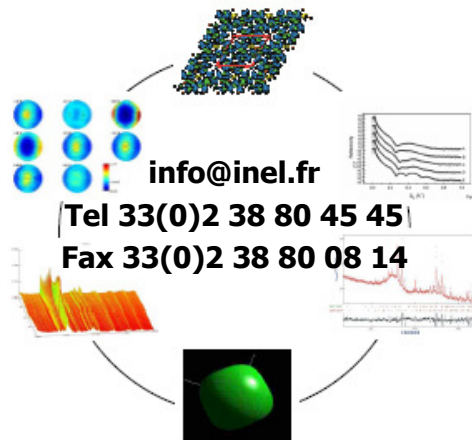


Reply coupon

I am interested in the workshop, and would like to receive the registration form by email.

First name :
Last name :
Title (Dr, Pr, Mr, Mrs, ...) :
Organization :
Laboratory :
Address :
.....
City :
Zip code :
Country :
Telephone :
Fax :
Email :

Don't forget to mention your email



info@inel.fr
Tel 33(0)2 38 80 45 45
Fax 33(0)2 38 80 08 14

General informations

Venue

The workshop will be held at Caen, France.

IUT, UCBN, CRISMAT ENSICAEN

Access

Caen is located in Normandy at 250 km west of Paris. Further more details are available in the registration form.

Contact

- ✓ Daniel Chateigner Professor, CRISMAT Laboratory, Caen: scientific coordinator
daniel.chateigner@ensicaen.fr
- ✓ Eric Berthier, INEL society: organization coordinator

info@inel.fr

<http://www.inel.fr>

Organizers

inel  <http://www.inel.fr>

<http://www.crismat.ensicaen.fr>



Second Announcement

1st Workshop

Combined Analysis Using X-ray and Neutron Scattering

June 28th – July 2nd, 2010
Caen (France)



Aim of the workshop

Is to allow students, academic and non-academic researchers to obtain information relating to the characterisation, structure, microstructure, phase, texture, stress and reflectivity by " Combined Analysis using X-ray and neutron scattering techniques" and relating to a number of samples and structures including : thin films bulk materials, materials with anisotropic crystal structures, polyphased materials, nanomaterials, multi- detectors, etc.

Each type of analysis will be considered individually and then integrated into a combined analysis program. Some specific examples will be studied using X-ray and neutron experimental data.

The objective is to bring together participant's from various fields and to provide an opportunity to discuss individual interests and experience.

X-ray equipment used at the CRISMAT laboratory and by INEL will be used to demonstrate technical aspects and to support the theoretical and practical issues of this course.

Our Team of Speakers

Daniel Chateigner, Caen (France)

Luca Lutterotti, Trento (Italia)

Henry Pillière (Inel), Artenay (France)

Olivier Perez, Caen (France)

Magali Morales, Caen (France)

Topics

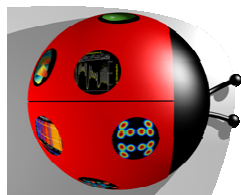
The workshop will cover many aspects of "Combined Analysis" by X-ray and neutron scattering, ranging from fundamental requirements to technically relevant industrial and academic applications.

- ✓ Diffraction technique, an overview
- ✓ Crystallography Texture Analysis
- ✓ Residual Stress Analysis
- ✓ Rietveld analysis
- ✓ Reflectivity analysis
- ✓ Phase analysis
- ✓ Phase and line broadening analysis
- ✓ The combined solution
- ✓ Using MAUD software

Pre-requisites

The necessary pre-requisites are as follows :

- ✓ Basic knowledge of crystallography and diffraction techniques
- ✓ Good practice in the use of computers
- ✓ If possible, bring your laptop for the practical sessions



Maud, Materials Analysis
Using Diffraction

<http://www.ing.unitn.it/~maud/>

Registration

If you are interested in this workshop, please send the reply coupon or an email entitled "Inel Crismat workshop" to

info@inel.fr / Fax 33(0)2 38 80 08 14

We will send you the registration form by return with the workshop program as well as the procedure to install the software on your PC before the start of the workshop. Payment conditions and tourism information will be included.

Registration fees

	Until June 1st, 2010	After June 1st, 2010
Student	400 €	500 €
Academic people	750 €	900 €
Industrial people	750 €	900 €

In order to ensure and encourage individual interaction the number of participants will be limited to 40.

Registration fees include :

- ✓ Admission and participation to the course
 - ✓ Coffee breaks, lunches, reception and conference dinner
 - ✓ Also program and workshop abstracts
- What is not included
- ✓ Hotel, transportation, other subsistence...

Registration Deadline
June 15th, 2010